

Incorporating Residual Stresses into Probabilistic Damage Tolerance Analysis



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- ✓ SMART|DT Overview
- ✓ Residual Stresses Modeling Software

✓ Are RS needed in PDTA?

- ✓ Sensitivity Study wrt. Remaining Useful Life

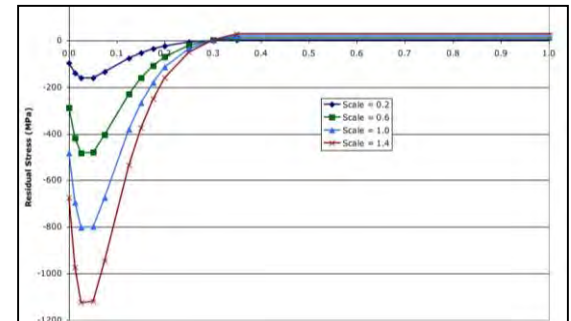
Probabilistic
RS Profile

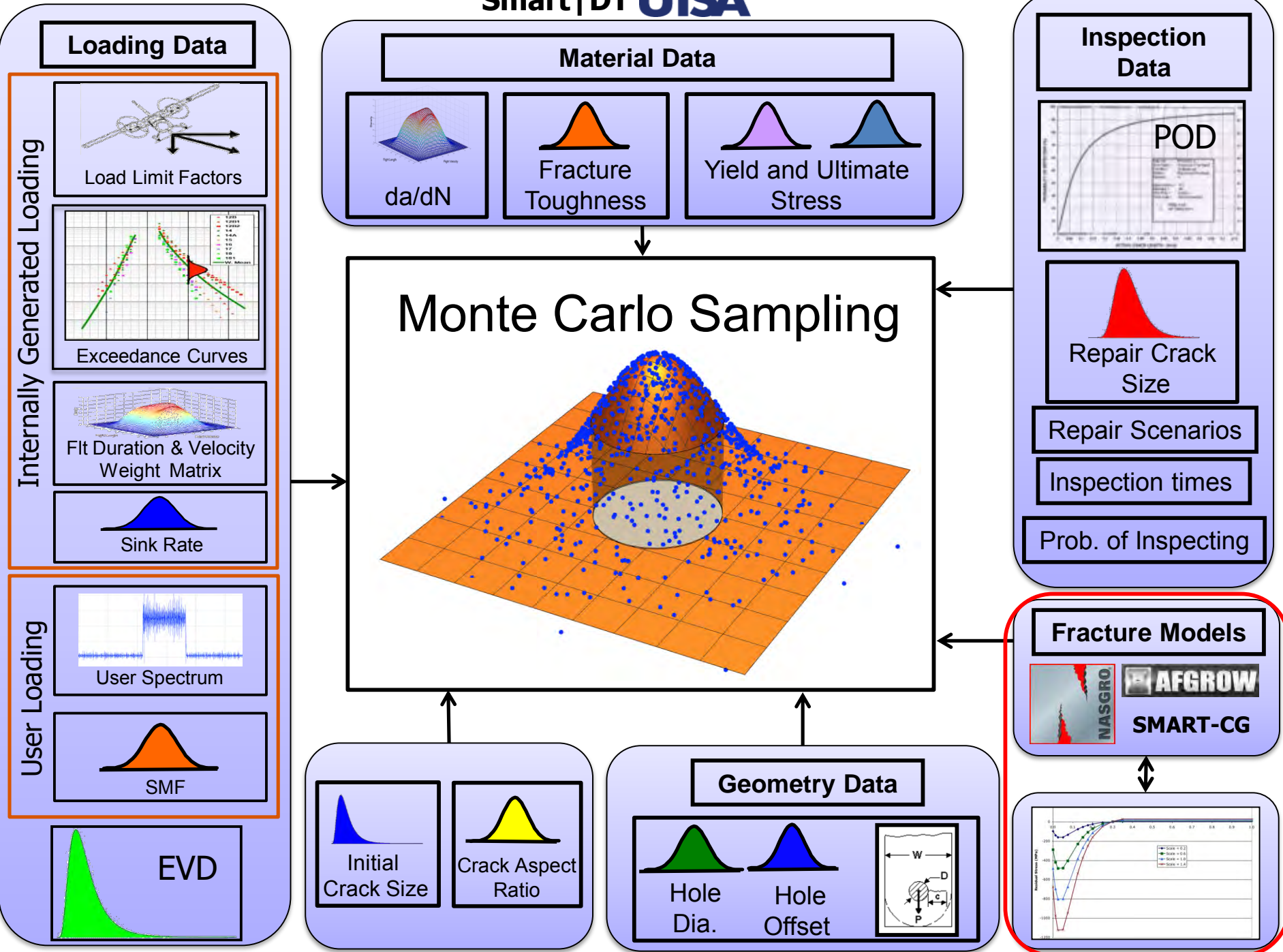
✓ Residual Stresses incorporated into PDTA

- ✓ Deterministic Residual Stresses

Deterministic
RS Profile

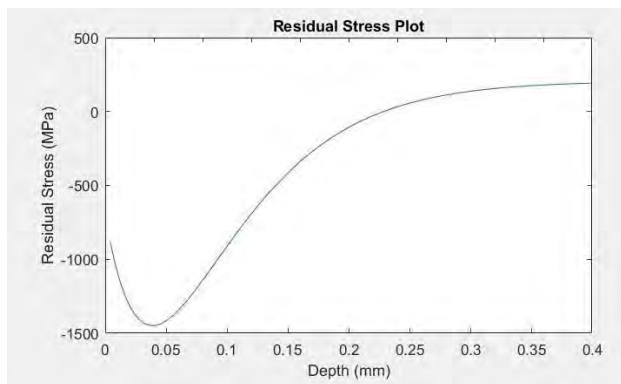
✓ Future Plans



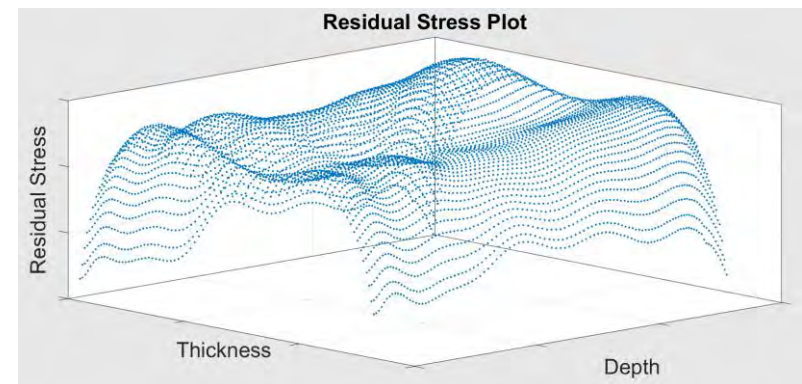




- Standalone executable to read experimental/simulated data and find the best deterministic and probabilistic fit parameters.
 - 3 Models Available (Expandable)
 - 2D (Stress vs Depth) and 3D (Stress vs Depth vs Thickness).
 - Read input data in .txt & .csv format



2D



3D



➤ Model I*

$$\sigma(x) = (ss - si + C_1x)Exp(-C_2x) + si$$

$$C_1 = \frac{\{(ss - si)(1 - Exp(-C_2B)) + siBC_2\}C_2}{(C_2B + 1)Exp(-C_2B) - 1}$$

➤ Model II**

$$\sigma(x) = A\sin(Bx + C)Exp\left(-\frac{x}{\lambda}\right)$$

➤ Model III (Polynomial Fit – Under Development)

$$\sigma(x) = Ax^5 + Bx^4 - Cx^3 + Dx^2 - Ex - F$$

* User Manual for ZENCRACK™ 7.1, Zentech International Ltd., Camberley, Surrey, UK, September, 2003.

** R. VanStone, "F101-GE-102 B-1B Update to Engine Structural Durability and Damage Tolerance Analysis Final Report (ENSIP), Vol. 2," General Electric, p. 5-2-2.



IN100ResidualStressProfilesGUI

all
RS1.csv
RS2.csv
RS3.csv
RS4.csv
RS5.csv
RS6.csv

Profile Type

Single Profile

Multiple Profile

Options

Model 2

Width

Run

A	2621.44	←		→
B	14.8527	←		→
C	-2.76741	←		→
lambda	0.0914038	←		→

Residual Stress Profiles

Residual Stress Plot



IN100ResidualStressProfilesGUI

Listbox

Profile Type

Single Profile

Multiple Profile

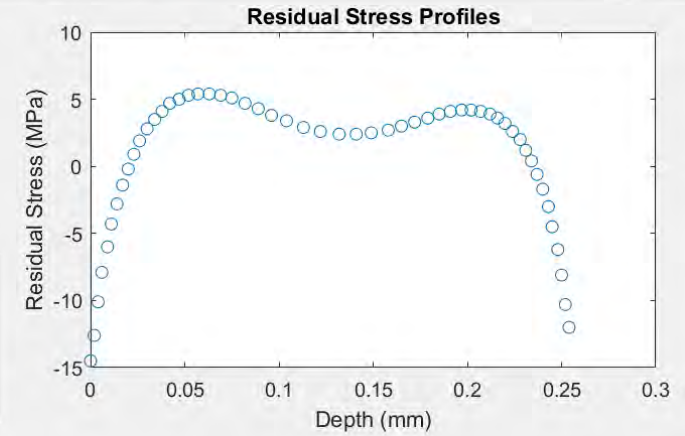
Options

Model 1

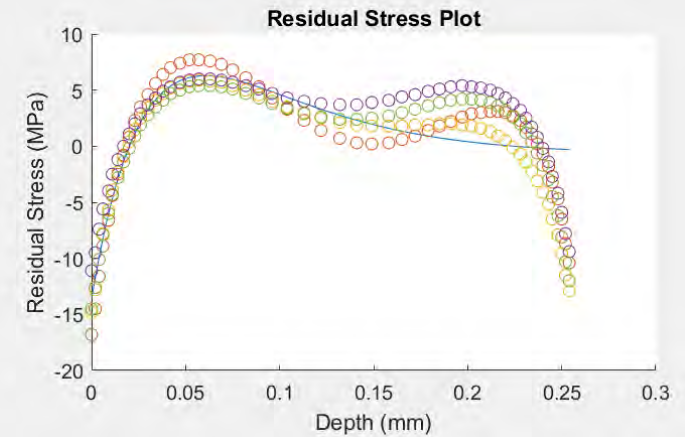
Width

Run

SS	-13.6089	<input type="text"/>	<input type="text"/>
SI	-0.696984	<input type="text"/>	<input type="text"/>
C1	23.7289	<input type="text"/>	<input type="text"/>



< 0.0 >

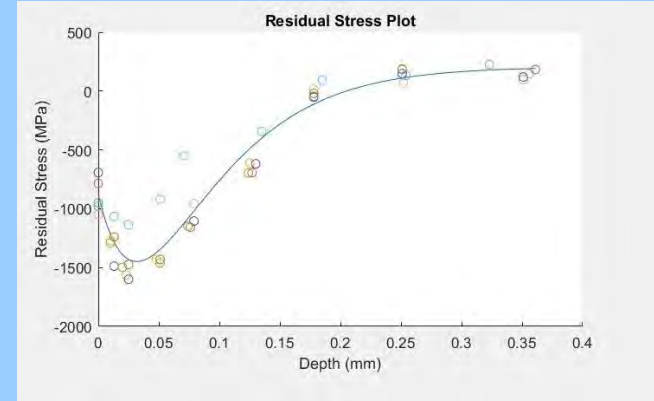




A2-1_stress.txt - Notepad

File	Edit	Format	View	Help
-1.928	0.254	0.000	-10.4	
-1.928	0.000	0.000	-16.8	
-1.928	0.252	0.000	-8.7	
-1.928	0.250	0.000	-6.5	
-1.928	0.248	0.000	-4.7	
-1.928	0.245	0.000	-3.2	
-1.928	0.243	0.000	-1.8	
-1.928	0.240	0.000	-0.7	
-1.928	0.237	0.000	0.2	
-1.928	0.234	0.000	1.1	
-1.928	0.231	0.000	1.7	
-1.928	0.228	0.000	2.3	
-1.928	0.224	0.000	2.7	
-1.928	0.220	0.000	3.0	
-1.928	0.216	0.000	3.1	
-1.928	0.212	0.000	3.1	
-1.928	0.207	0.000	3.0	
-1.928	0.202	0.000	2.9	

RS
Mod



Mean and Standard Deviation Parameters

	Mean	St dev
ss	-879.16	58.58
si	205.68	9.448
c2	20.872	1.050

Correlation Parameters

	ss	si	c2
ss	1	-0.214	0.402
si	-0.214	1	-0.796
c2	0.402	-0.796	1



Are probabilistic RS needed in PDTA?

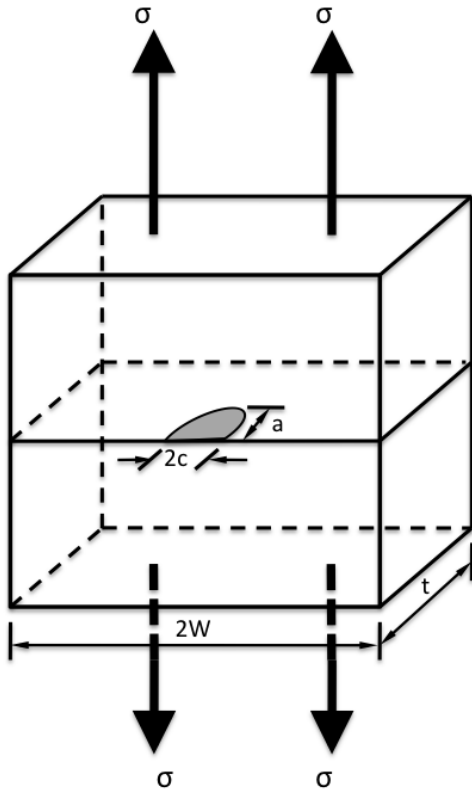
Sensitivity Study wrt Remaining
Useful Life



- Random variable sensitivity wrt remaining useful life

Variable Name	Type
Geometry (W)	Random
Geometry (t)	Random
Initial Crack Size (a)	Random
Initial Crack Size (c)	Random
Fracture Toughness (Kc)	Random
Residual Stress	Random
Paris Coefficients (C, m)	Random
Loading	Random
Walker m parameter	Deterministic
Stress Gradient (die out)	Deterministic
Threshold Kth	Deterministic

Residual Stress Sensitivity Study



Parameter	Mean (m)	COV
$W = 2t$	0.5	10%
t	0.25	10%

Residual Stress Sensitivity Study

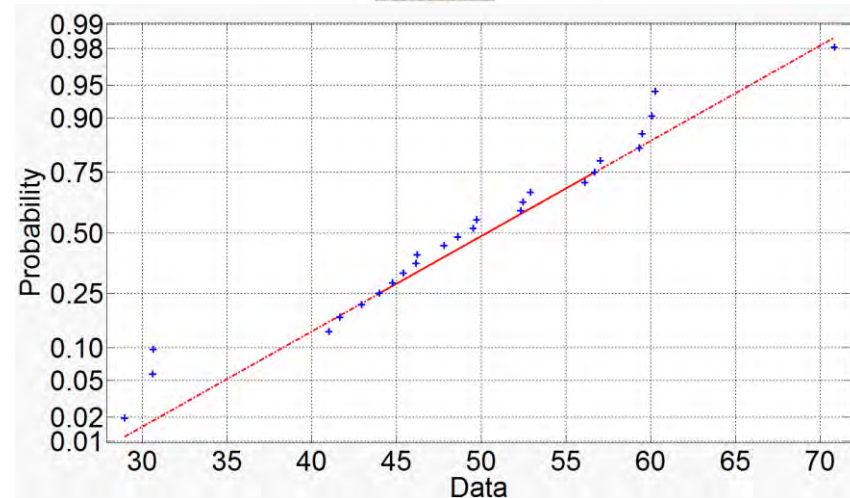
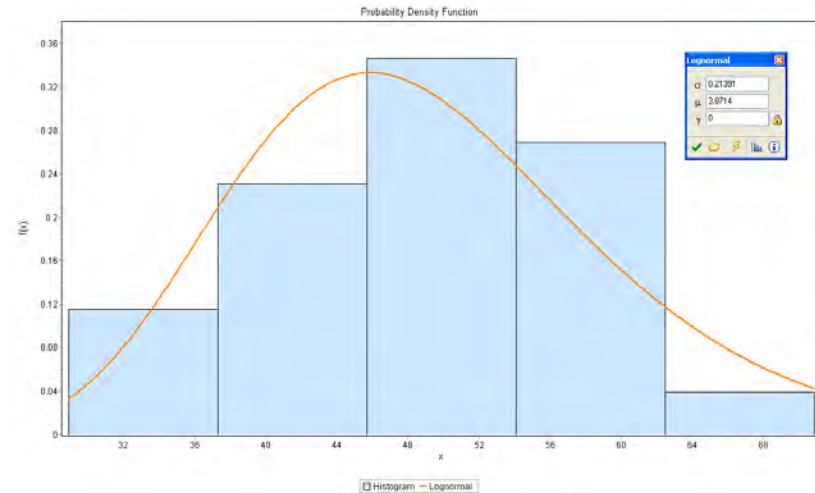


Raw Data

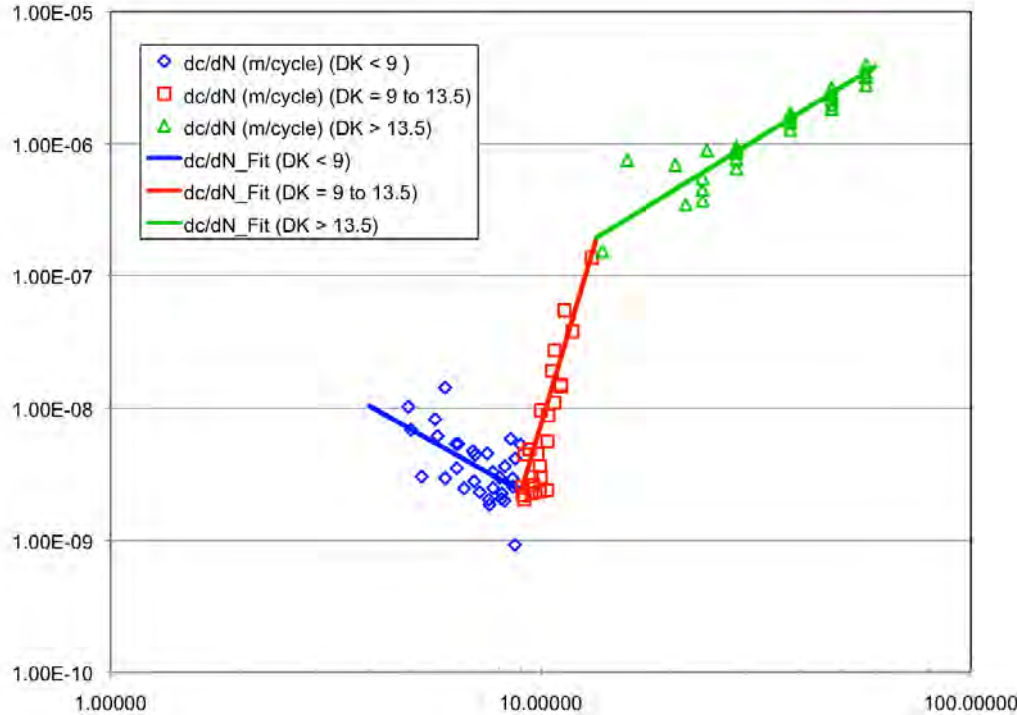
Equivalent Semi-elliptical Crack Depth (a/c=1) (um)

42.94
43.98
28.93
48.63
52.48
60.26
52.32
47.82
44.75
59.34
70.83
59.49
41.65
56.68
49.72
41.01
30.65
45.40
57.04
52.90
46.20
49.53
56.11
60.08
46.14
30.60

Lognormal distribution with histogram and lognormal probability plot
 $LN\sim(3.871, 0.23)$



Residual Stress Sensitivity Study



Curve Section	C	m
$\Delta K > 13$	1.602E-09	1.8753
$9 < \Delta K < 13$	2.425E-20	11.3580
$\Delta K < 9$	1.306E-07	-1.8293

SAS Code to find the regression parameters and the variation on the parameters (Using simple linear regression)

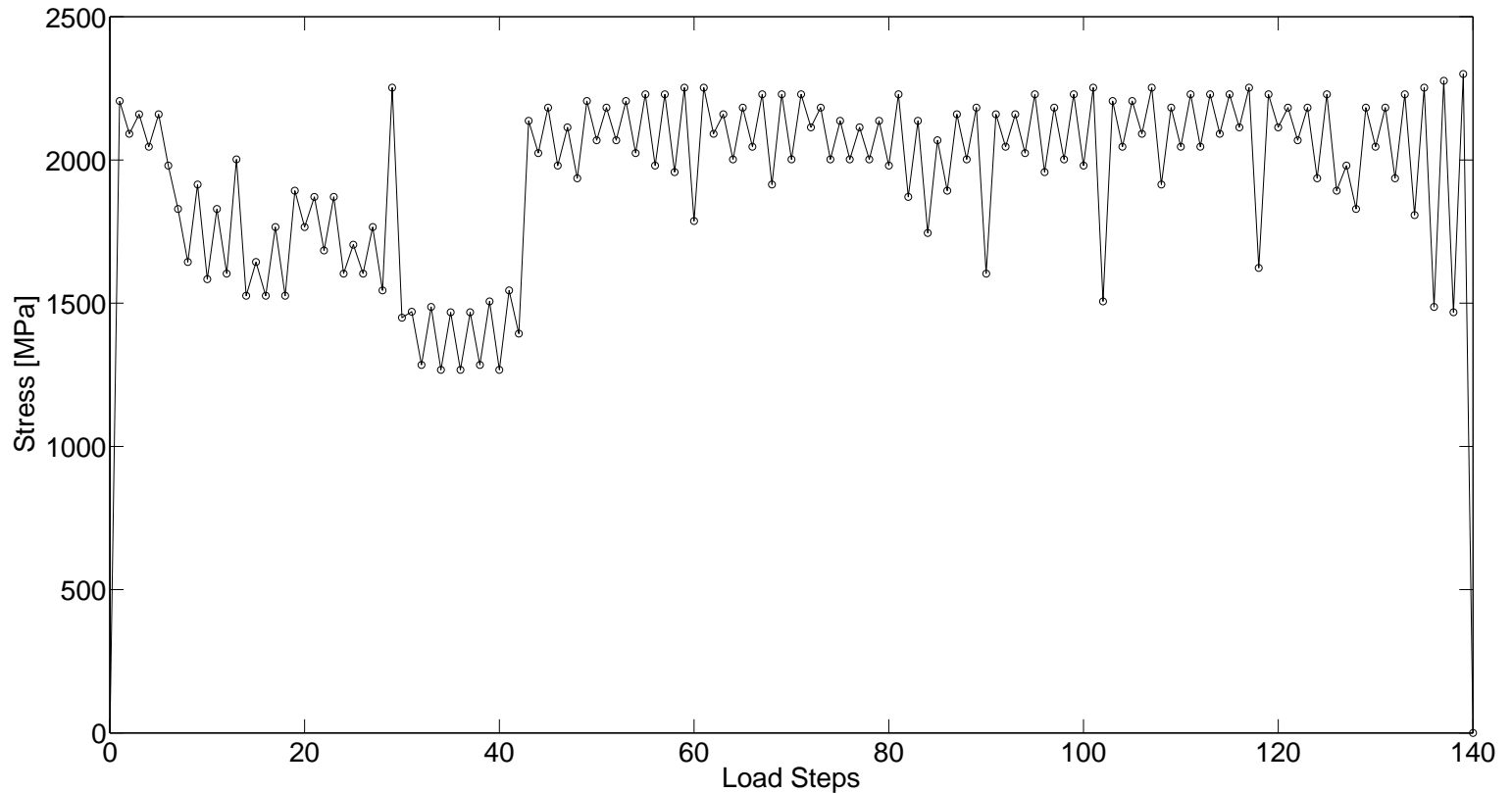
$$\frac{da}{dN} = C_1 \left[(DK) (1 - R)^{(m-1)} \right]^{n_1} \quad DK < b$$

$$\frac{da}{dN} = C_2 \left[(DK) (1 - R)^{(m-1)} \right]^{n_2} \quad DK \geq b$$

$$b = \frac{\log_{10}(C_1) - \log_{10}(C_2)}{n_2 - n_1}$$



Variable Amplitude Loading





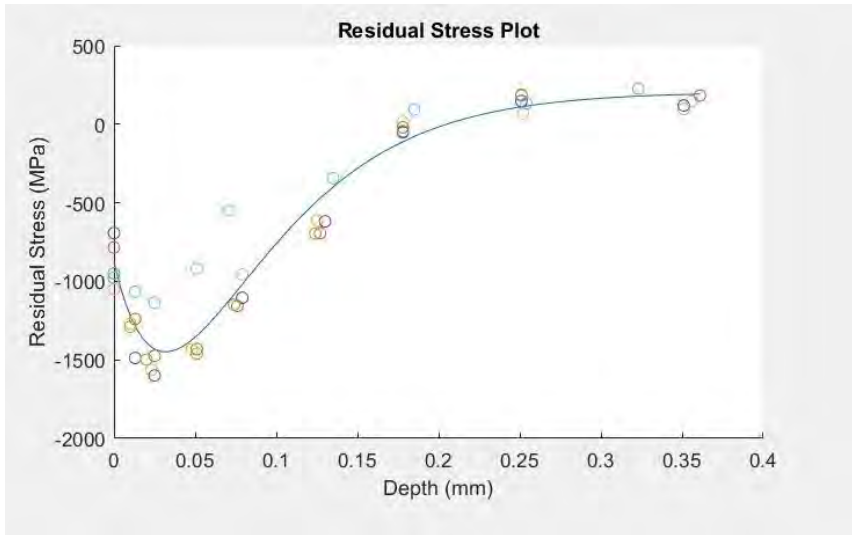
➤ Shot Peening Residual Stress Profile (Random)

Mean and Standard Deviation Parameters

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ss	-879.16	58.58
si	205.68	9.448
c2	20.872	1.050

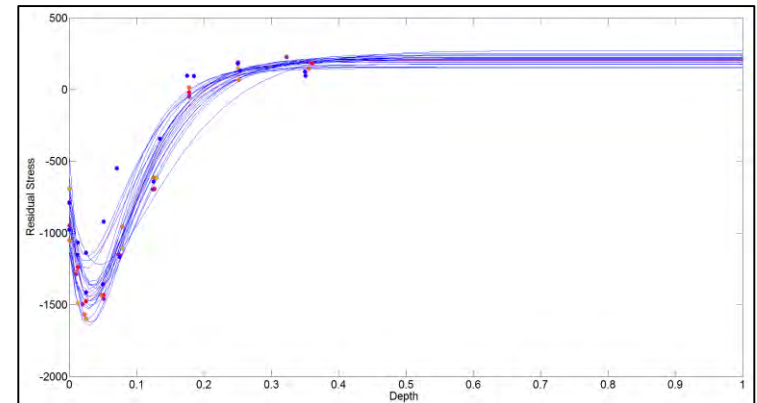
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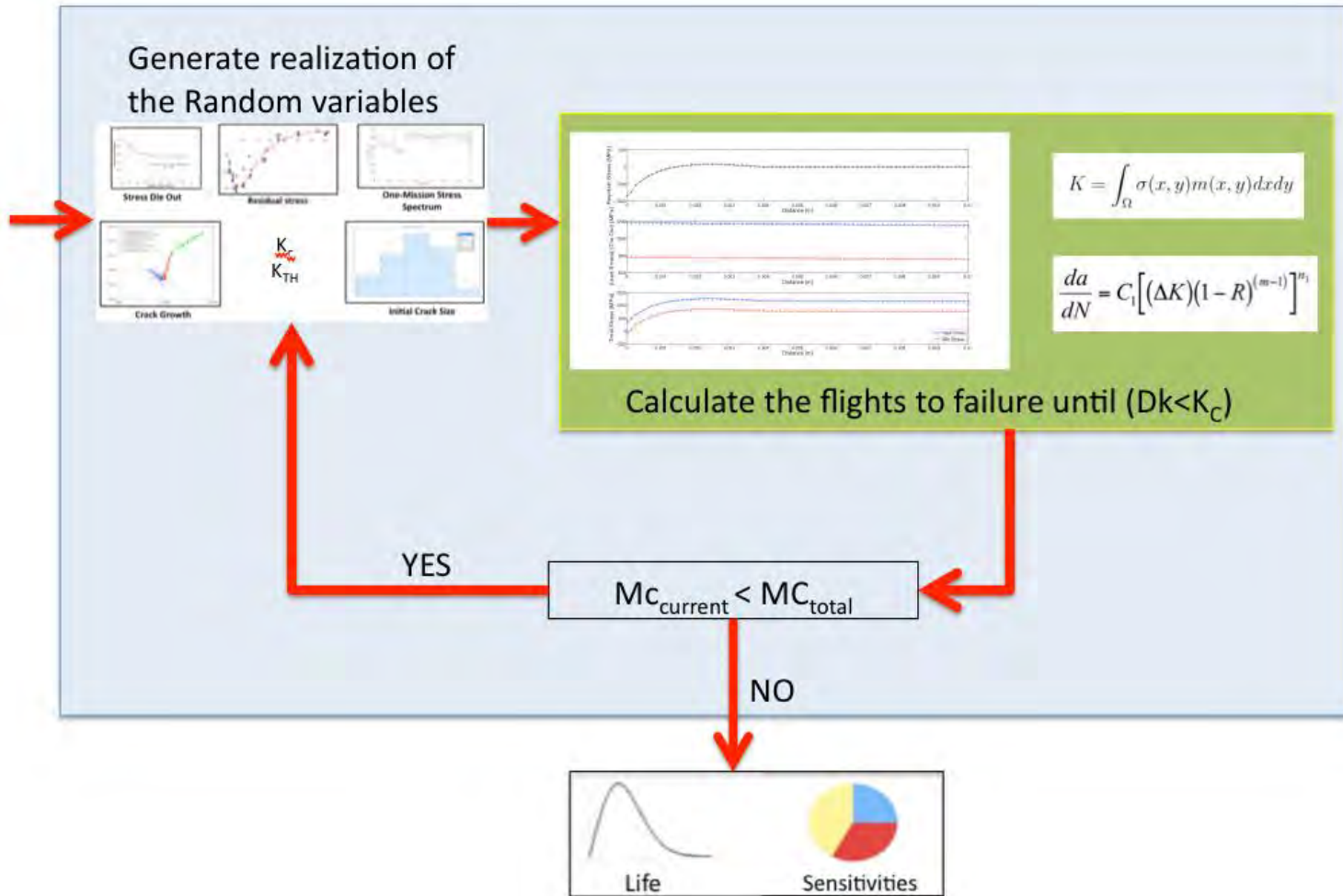


$$\sigma(x) = (ss - si + c_1 x) \text{Exp}[-C_2 x] + si$$

$$C_1 = \frac{\{(\sigma_s - \sigma_i)(1 - \text{Exp}[-C_2 B]) + \sigma_i B C_2\} C_2}{(C_2 B + 1) \text{Exp}[-C_2 B] - 1}$$



Residual Stress Sensitivity Study

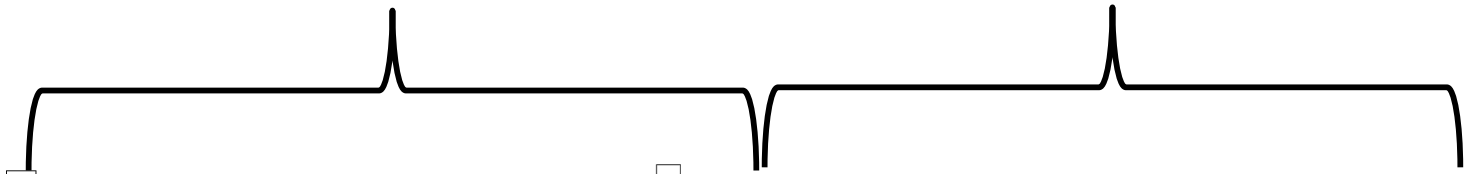


Sensitivity Results



$$\bar{S}_\theta = \frac{\partial P}{\partial \theta} \cdot \theta$$

$$S_i = \frac{V_{X_i} (E_{X \sim i}(Y/X_i))}{V(Y)}$$



Input variable	Sensitivity Value	Importance	Sensitivity Value	Importance
C2	0.30	1	0.473479	1
Si	0.18	2	0.329348	2
Paris	0.16	3	0.150957	4
Ss	0.09	4	0.198532	3
ai	0.04	5	0.092150	5
Loading	0.01	6	0.014135	6
W	0.0026	7	0.003211	7
Kic	0.0009	8	0.001111	8
t	0.000009	9	1.11E-05	9

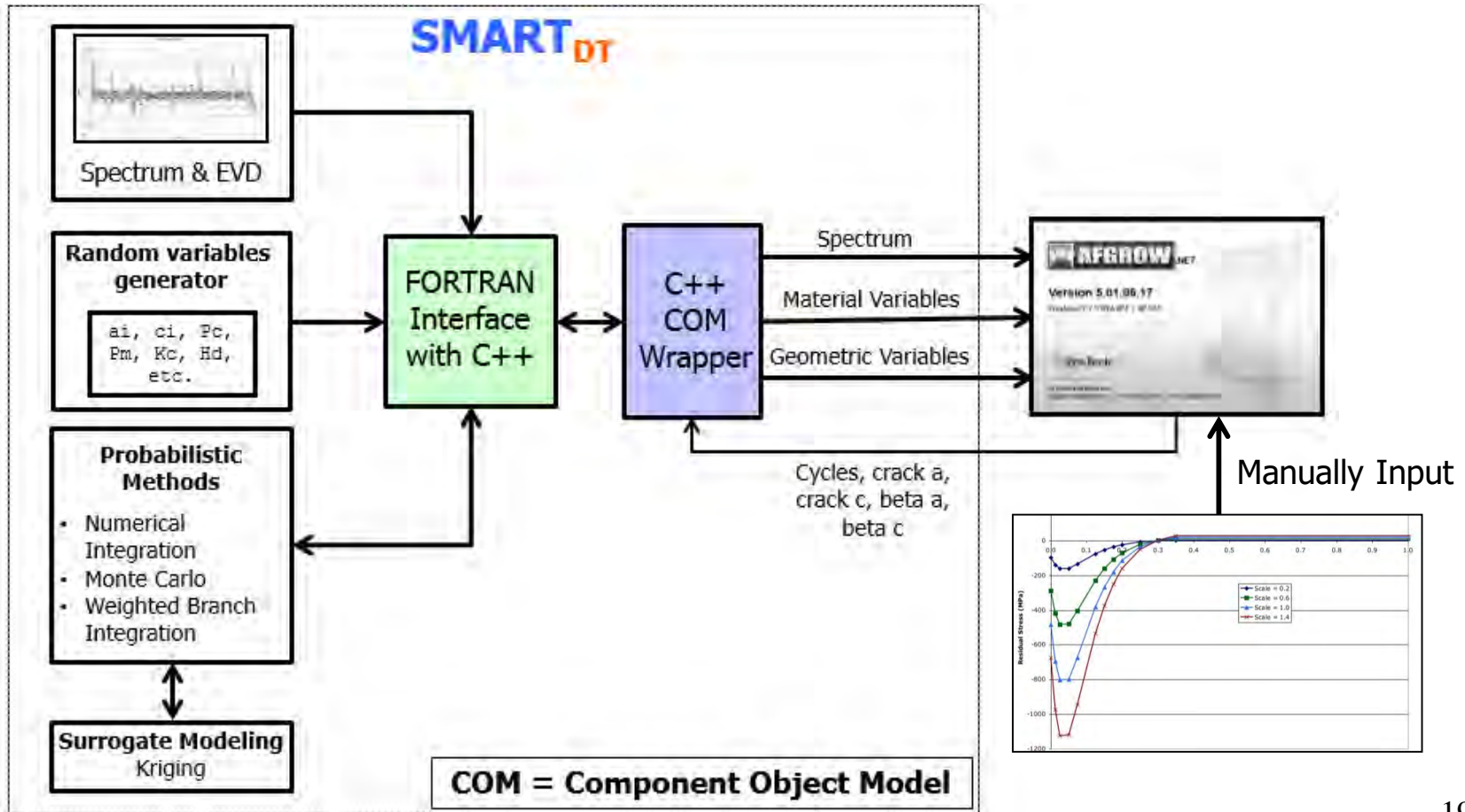
Results are problem dependent



Residual Stress Effect on SFPOF Using Deterministic Residual Stress Profile



➤ SMART-AFGROW interface.

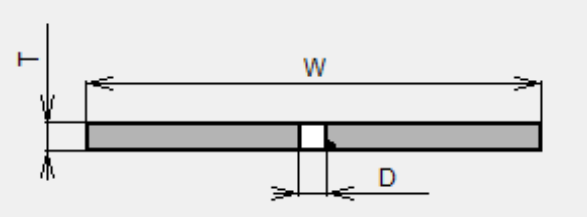


Input Parameters

Deterministic RS Example



Corner crack @ hole



Parameter	Value
T	0.09 in
W	4.0 in
D	0.25 in

Mat. Prop.

Walker Equation Data

The Walker equation extended the early Paris equation by allowing the shift in da/dN vs. ΔK as a function of stress ratio (R). The equation may be used in several segments to attempt to model the sigmoidal shape of the data.

Use up to 5 sets of values of 'C', 'n', and 'm'

Number of Sets: 1

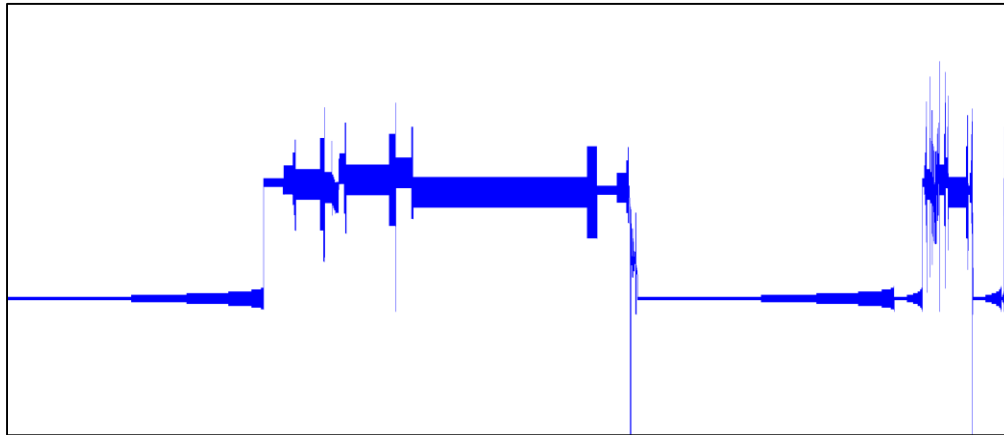
Set	C	n	m
1	2.6300e-009	3.200000002	0.5
2	1e-008	3	0.5
3	1e-008	3	0.5
4	1e-008	3	0.5
5	1e-008	3	0.5

Material name: User defined data

Coefficient of Thermal Expansion: 1.249999968 Young's Modulus: 10600
 Yield Strength, YLD: 56.00000023 Poisson's Ratio: 0.330000011

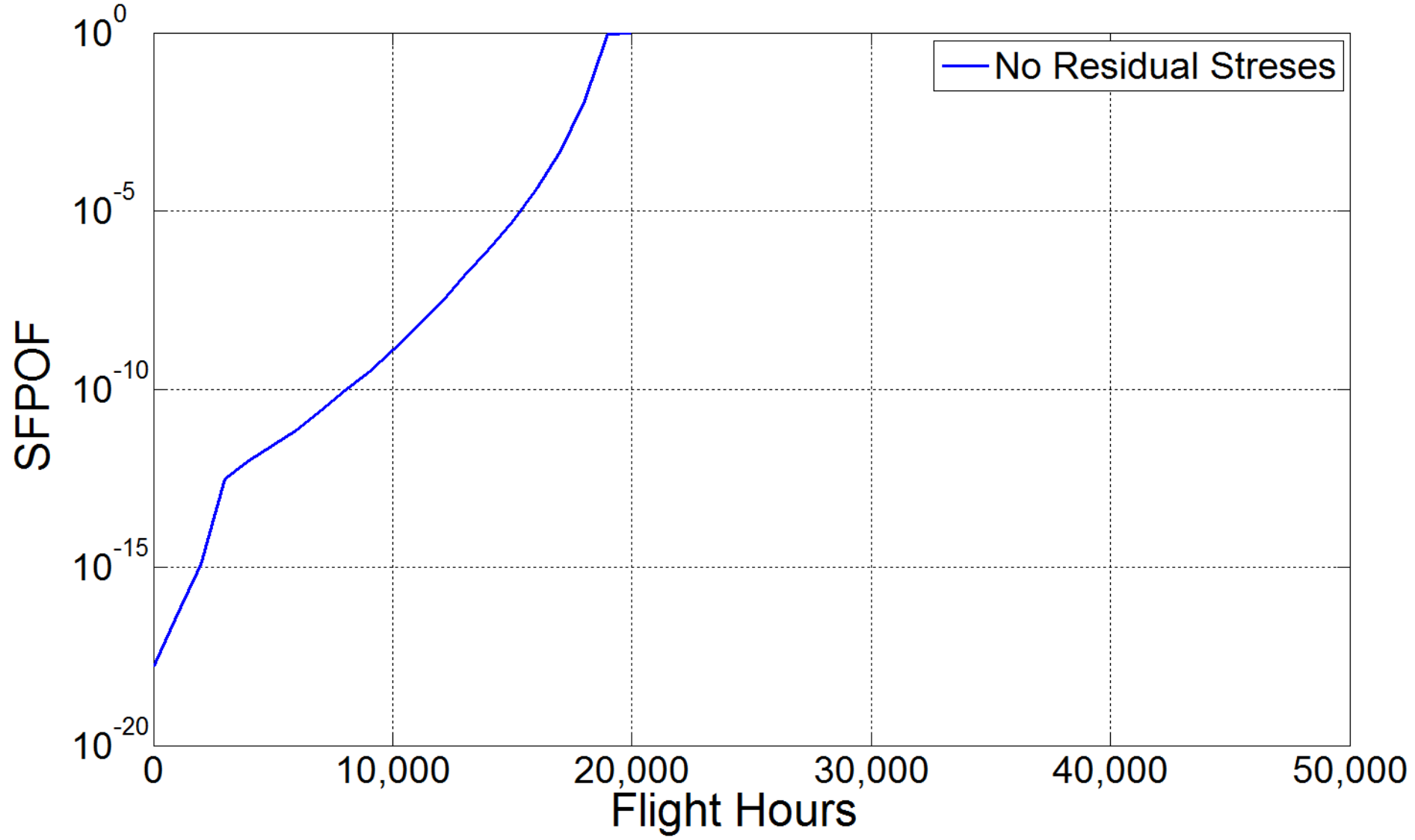
Plane Stress Fracture Toughness, KIC: 100
 Plane Strain Fracture Toughness, KIC: 35 Lower limit on R shift (0. -1): -0.99
 Delta K threshold value @R=0: 2 Upper limit on R shift (< 1): 0.99

OK Cancel Save Read Apply

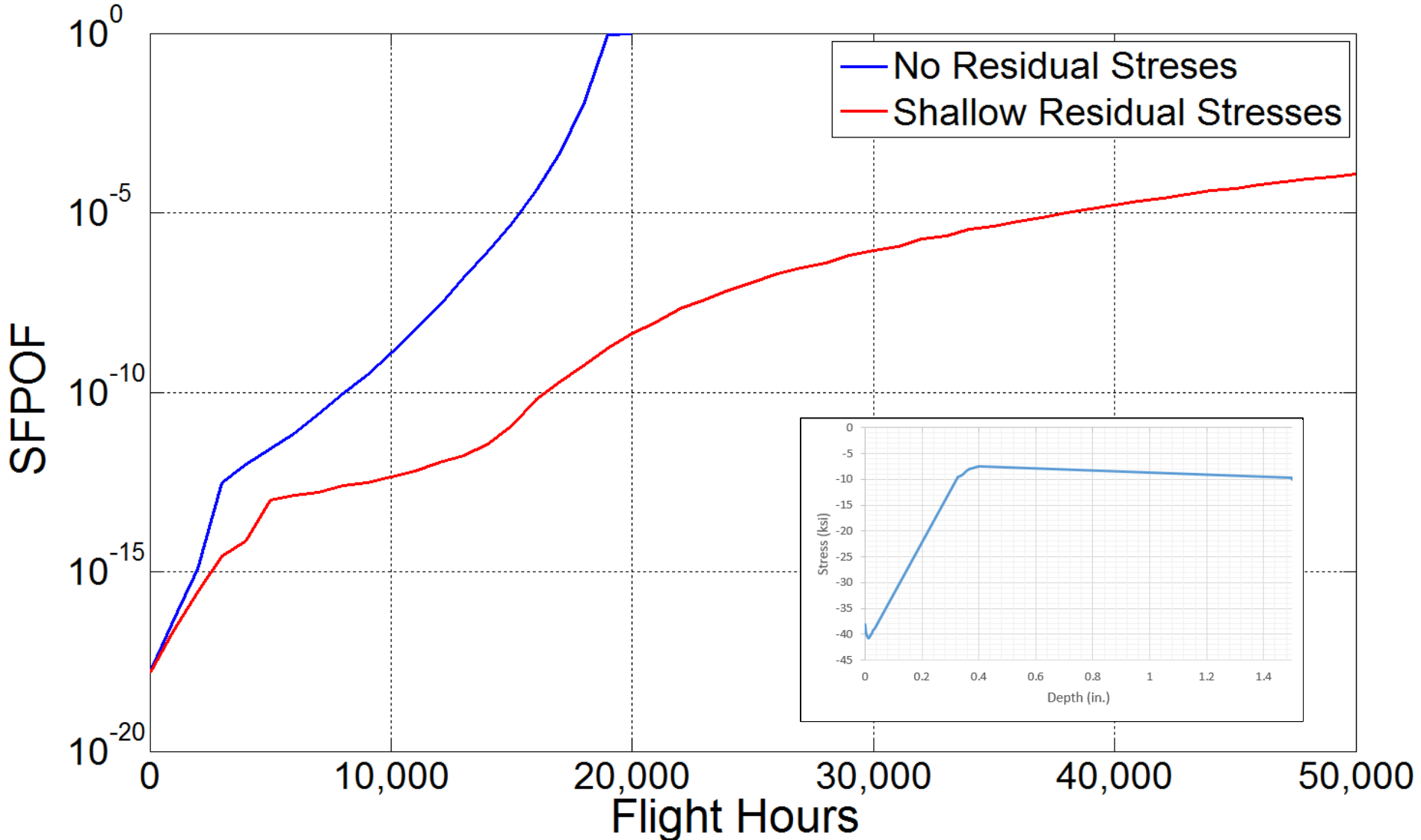


Random Variables	Value
Fracture Toughness Distribution (Normal)	Mean = 34.5ksi $\sqrt{\text{in}}$, Standard Deviation = 3.8 ksi $\sqrt{\text{in}}$.
Initial & Repair Lognormal Size Distribution (a & c) (Lognormal)	Mean = 0.01 in, Standard Deviation = 0.001 in.
Extreme Value Distribution (Gumbel)	Location = 14.5, Scale = 0.8, and Shape = 0.0
Inspections (5,000 & 10,000)	POD Lognormal Mean = 0.07in, Standard Deviation = 0.06

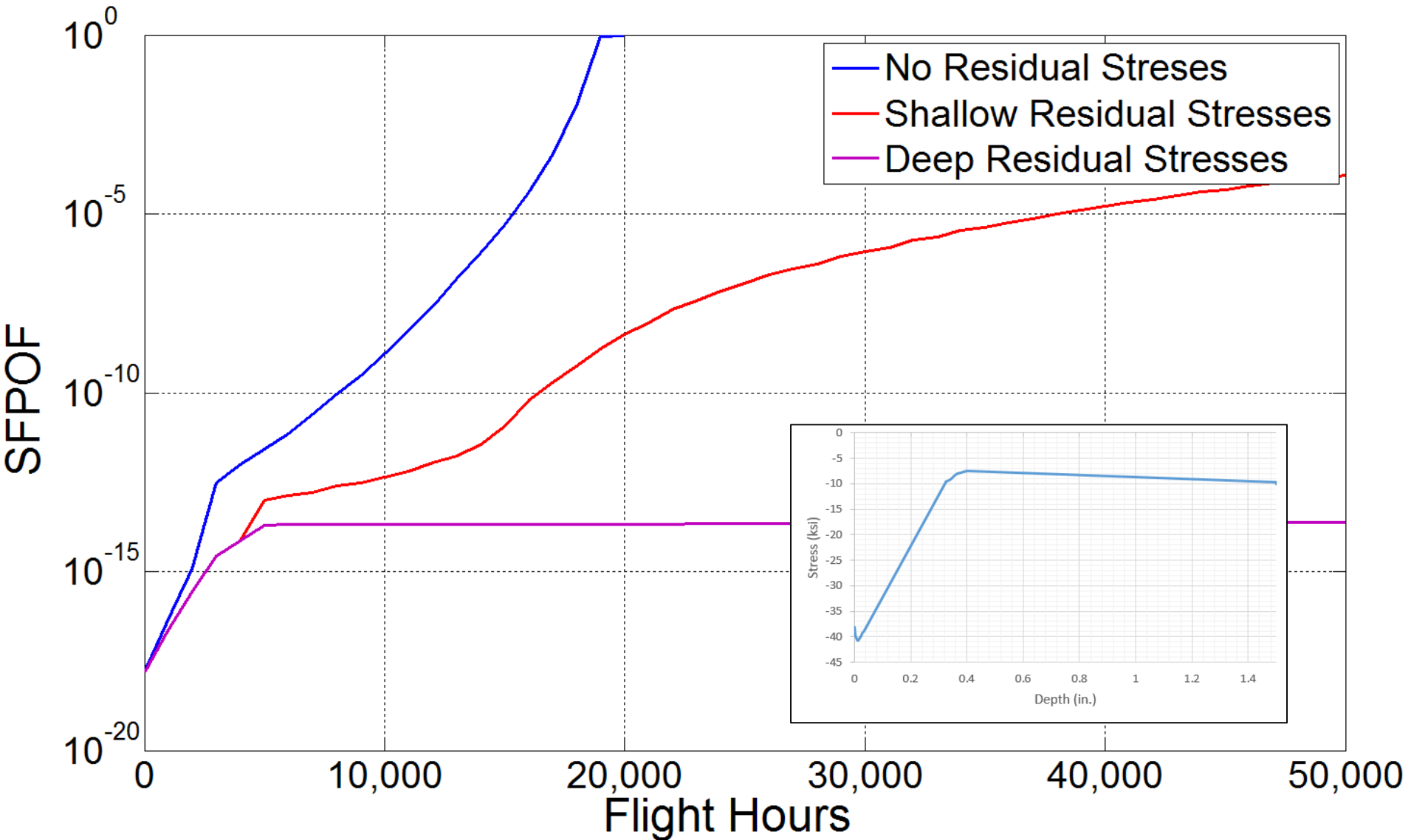
Results without Inspections

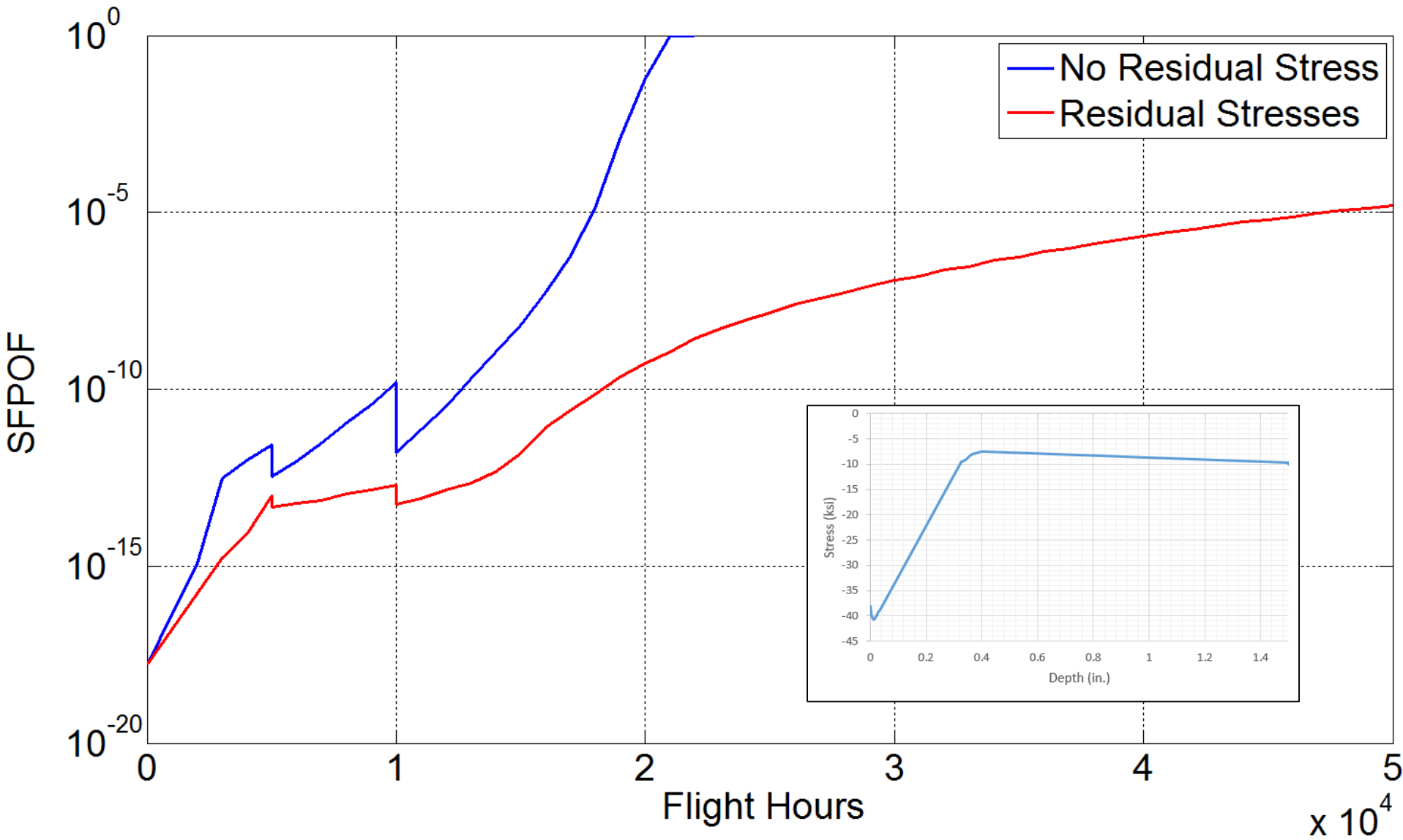


Results without Inspections

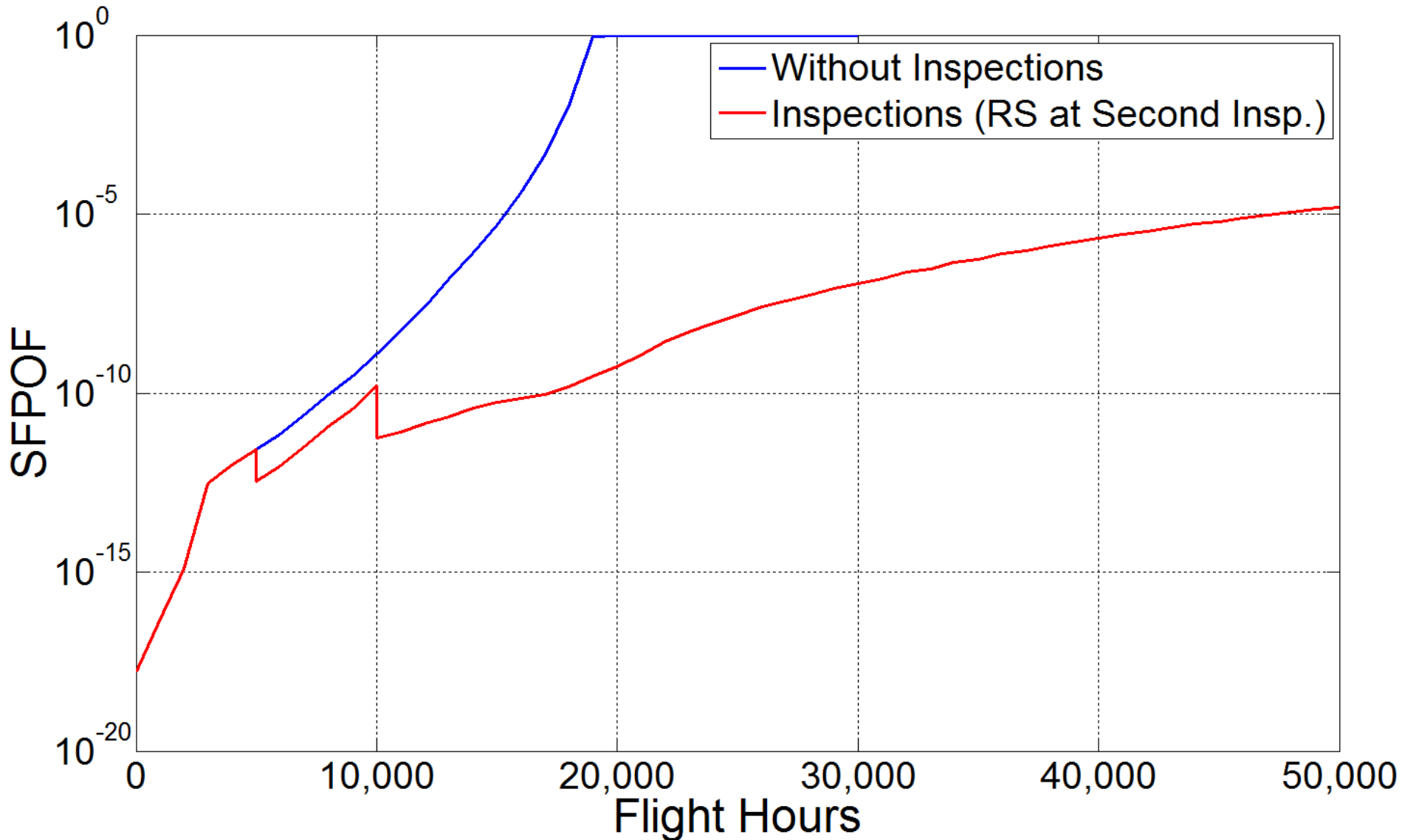


Results without Inspections





Inducing RS at the Second Inspections





An Ultrafast Crack Growth Lifting Algorithm for Probabilistic Damage Tolerance Analysis



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University of Texas at San Antonio

Juan D. Ocampo
St. Mary's University, San Antonio

The Aircraft Airworthiness & Sustainment (AA&S) Conference
Jacksonville, FL. May– 2018.



- ✓ Probabilistic damage tolerance analysis requires very small probabilities, e.g., $1E-9$
- ✓ Previous methods allow for a deterministic crack growth curve and do not consider randomness in crack growth rate properties.
- ✓ Surrogate models, e.g., Kriging, can be used to speed up the analysis but are still very time consuming.
- ✓ Hence an ultrafast crack growth lifing code was developed.



- 1) Create an equivalent constant amplitude from an arbitrary spectrum
- 2) Use an *internal* adaptive time stepping RK algorithm to grow the crack
- 3) Collect the top 100 (or so) damaging realizations for further examination and potential reanalysis



Thank you!!

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